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William R. Busing
Henri A. Levy

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by William R. Busing and Henri A. Levy

Chemistry Division, Oak Ridge National Laboratory,
Oak Ridge, Tennessee 37830

ABSTRACT

Methods are derived for calculations useful in the operation of 3- and 4-circle x-ray or neutron single-crystal diffractometers. These include: (1) establishing the sample orientation from the cell parameters and the observed angles for two reflections, or from the observed angles for three reflections only, (2) calculating the angles for observing a given reflection either in a special setting or at a specified azimuthal angle, (3) obtaining the vectors needed for calculating absorption corrections, and (4) using observations of several reflections to refine cell and orientation parameters by the method of least squares. Algorithms for many of the procedures are presented in an appendix.

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It appears that 3- and 4-circle x-ray or neutron diffractometers will be used increasingly in the next few years. For this reason it seems desirable to present in a compact way some mathematical procedures which can be used with these instruments to establish sample orientation and to calculate setting angles. All of the techniques described here have been tested and found useful in our work with the Oak Ridge automatic 3-circle neutron diffractometer (Busing, Smith, Peterson & Levy, 1964) and the Oak Ridge computer-controlled 4-circle x-ray diffractometer (Busing, Ellison & Levy, 1965). Some of these calculations have been discussed in a less general way by others (Furnas & Harker, 1955; Arndt & Phillips, 1957; Willis, 1961; Santoro & Zocchi, 1964; Wooster, 1964; Rollett, 1965).

Calculations of this type will almost certainly be performed by means of a high-speed computer, and algorithms for many of the procedures are presented in the Appendix using the Algol 60 language. Matrix arithmetic is used extensively because the expressions in expanded form would often be too cumbersome to be useful.

DEFINITION OF DIFFRACTOMETER ANGLES

The instrument arrangement which we will take as standard is illustrated schematically in Fig. 1a, which shows the instrument axis as vertical. Perpendicular to this axis and passing through the instrument center is a horizontal plane.

The primary beam lies in this horizontal plane and is directed at the sample which is located at the instrument center. The counter also lies in the horizontal plane and rotates about the instrument axis to make an angle 2θ with the primary beam direction. The instrument angles may be adjusted so that a diffracted beam is horizontal and enters the center of the counter.

Moving the counter through an angle of 2θ causes the crystal orienter and sample to turn through an angle of θ about the vertical axis. The orienter may also be rotated independently through an additional angle ω about the same axis. In this way the χ axis which lies in the horizontal plane is positioned to make an angle of $\theta + \omega$ with the primary beam direction. The reflecting-plane normal (scattering vector), which bisects the angle between the diffracted beam and the reverse primary beam, thus makes an angle of ω with the plane of the χ ring.

The ϕ shaft is supported from the χ ring which permits the ϕ axis to be set at an angle χ from the vertical instrument axis. The sample is assumed to be rigidly attached to the ϕ shaft so that it can be turned about this axis.

The diffractometer with all angles set to zero is shown schematically in Fig. 1b. The senses of θ, 2θ, ω, and χ are defined by Fig. 1a, which shows the instrument with these angles in the first quadrant. The zero position for ϕ is chosen arbitrarily, and the figure shows the direction of rotation which increases this angle.

Also shown in Fig. la is the angle Ψ which measures the rotation of the sample about the normal to the reflecting plane of interest. With this type of diffractometer Ψ motion is achieved not by the rotation of a single shaft but rather as the result of a combination of changes in ω, χ, and ϕ. The choice of zero for Ψ will be discussed below.

These definitions will be assumed throughout this paper, but the results can be applied to instruments with other conventions by making the appropriate transformations. The 3-circle diffractometer can usually be regarded as a special case for which ω is constrained to be zero.

COORDINATE TRANSFORMATIONS

Let $\underset{\sim}{v}$ be the column vector describing some physical vector $\underset{\simeq}{v}$ in terms of the right-handed reciprocal lattice vectors $\underset{\simeq}{b}_i$ so that

$$\underset{\simeq}{v} = \sum_{i=1}^{3} v_i \underset{\simeq}{b}_i . \qquad (1)$$

It will be convenient to define several systems of right-handed cartesian axes which may also be used to describe $\underset{\simeq}{v}$.

Let $\underset{\sim}{v}_c$ be the description in terms of the <u>crystal cartesian</u> axes which are attached in some way to the reciprocal lattice. If we choose the x-axis parallel to $\underset{\simeq}{b}_1$, the y-axis in the plane of $\underset{\simeq}{b}_1$ and $\underset{\simeq}{b}_2$, and the z-axis perpendicular to that plane, then

$$\underset{\sim}{v}_c = \underset{\sim}{B}\ \underset{\sim}{v} \tag{2}$$

where

$$\underset{\sim}{B} = \begin{pmatrix} b_1 & b_2\cos\beta_3 & b_3\cos\beta_2 \\ 0 & b_2\sin\beta_3 & -b_3\sin\beta_2\ \cos\alpha_1 \\ 0 & 0 & 1/a_3 \end{pmatrix} \tag{3}$$

Here the a_i's and α_i's and the b_i's and β_i's are the direct and reciprocal lattice parameters, respectively. This expression is related to transformations discussed by Patterson (1959a) and by Rollett (1965), and although our crystal cartesian system is different from those chosen by these authors, nothing in this paper except the above expression for matrix $\underset{\sim}{B}$ depends upon this choice. The algorithm generate B given in the Appendix produces this matrix from the direct cell parameters.

Let the ϕ-axis system be a set of cartesian axes rigidly attached to the ϕ shaft of the instrument. When all instrument angles are set to zero this system has the orientation shown in Fig. 1b with the x-axis along the scattering vector, the y-axis in the direction of the primary beam, and the z-axis in the vertical instrument-axis direction.

Let $\underset{\sim}{U}$ be the orthogonal matrix which relates this ϕ-axis system to the crystal cartesian system so that

$$\underset{\sim}{v}_\phi = \underset{\sim}{U}\ \underset{\sim}{v}_c. \tag{4}$$

$\underset{\sim}{U}$ will be called the orientation matrix since it depends on the way in which the crystal has been mounted and also on the

arc settings if a goniometer head is used. $\underset{\sim}{U}$ may readily be derived for certain special orientations, and in later sections we will consider general ways of obtaining $\underset{\sim}{U}$.

In a similar way let us define three more cartesian systems attached to the χ, ω, and θ axes, respectively, and coincident with the ϕ-axis system when all instrument angles are zero. The vector $\underset{\approx}{v}$ is transformed to these systems as follows:

$$\underset{\sim}{v}_{\chi} = \underset{\sim}{\Phi}\, \underset{\sim}{v}_{\phi}, \tag{5}$$

$$\underset{\sim}{v}_{\omega} = \underset{\sim}{X}\, \underset{\sim}{v}_{\chi}, \tag{6}$$

$$\underset{\sim}{v}_{\theta} = \underset{\sim}{\Omega}\, \underset{\sim}{v}_{\omega}, \tag{7}$$

where

$$\underset{\sim}{\Phi} = \begin{pmatrix} \cos\phi & \sin\phi & 0 \\ -\sin\phi & \cos\phi & 0 \\ 0 & 0 & 1 \end{pmatrix}, \tag{8}$$

$$\underset{\sim}{X} = \begin{pmatrix} \cos\chi & 0 & \sin\chi \\ 0 & 1 & 0 \\ -\sin\chi & 0 & \cos\chi \end{pmatrix}, \tag{9}$$

and

$$\underset{\sim}{\Omega} = \begin{pmatrix} \cos\omega & \sin\omega & 0 \\ -\sin\omega & \cos\omega & 0 \\ 0 & 0 & 1 \end{pmatrix}. \tag{10}$$

Finally let us define a <u>laboratory system</u> fixed with respect to the primary beam and a <u>2θ-axis system</u> attached to the counter shaft. Again these cartesian axes will be chosen

to coincide with the ϕ-axis system when all the instrument angles are zero. A vector $\underset{\sim}{v}$ is transformed to these systems as follows:

$$\underset{\sim}{v}_{\ell} = \underset{\sim}{\Theta}\ \underset{\sim}{v}_{\theta} = \underset{\sim}{N}\ \underset{\sim}{v}_{\omega} \tag{11}$$

$$\underset{\sim}{v}_{2\theta} = \underset{\sim}{\mathfrak{G}}\ \underset{\sim}{v}_{\theta} = \underset{\sim}{M}\ \underset{\sim}{v}_{\omega} \tag{12}$$

where

$$\underset{\sim}{\Theta} = \begin{pmatrix} \cos\theta & \sin\theta & 0 \\ -\sin\theta & \cos\theta & 0 \\ 0 & 0 & 1 \end{pmatrix}, \tag{13}$$

$$\underset{\sim}{N} = \underset{\sim}{\Theta}\ \underset{\sim}{\Omega} = \begin{pmatrix} \cos\nu & \sin\nu & 0 \\ -\sin\nu & \cos\nu & 0 \\ 0 & 0 & 1 \end{pmatrix} \tag{14}$$

with $\nu = \omega + \theta$,

and

$$\underset{\sim}{M} = \underset{\sim}{\mathfrak{G}}\ \underset{\sim}{\Omega} = \begin{pmatrix} \cos\mu & \sin\mu & 0 \\ -\sin\mu & \cos\mu & 0 \\ 0 & 0 & 1 \end{pmatrix} \tag{15}$$

with $\mu = \omega - \theta$.

All angles except χ can be considered to be left-handed rotations about their respective axes.

BASIC DIFFRACTOMETER EQUATIONS

Throughout this paper we will assume the following ideal conditions: a perfect diffractometer, a centered point sample with no mosaic spread, and a point source of monochromatic radiation. The deviations from these assumptions

which are found in practice usually do not invalidate the calculations to be described. One exception is the presence of the α-doublet in the x-ray spectrum, the effect of which will be mentioned in the section on least-squares refinement.

To observe a reflection in the ideal diffractometer setting shown in Fig. 1a it is necessary for θ to satisfy the Bragg equation and for the plane normal to lie along the x-axis of the θ coordinate system. If h, k, and ℓ are the indices of the reflecting plane then the corresponding column vector in the reciprocal lattice system is

$$\underset{\sim}{h} = \begin{pmatrix} h \\ k \\ \ell \end{pmatrix} . \tag{16}$$

The length q of this vector which is the reciprocal of the interplanar spacing in Angstrom units is readily found from its components in any one of our cartesian systems. For example

$$q = (h_{c1}^{\ 2} + h_{c2}^{\ 2} + h_{c3}^{\ 2})^{1/2} \tag{17}$$

where $\underset{\sim}{h}_c = \underset{\sim}{B}\ \underset{\sim}{h}$.

The Bragg equation is then

$$\sin \theta = \lambda q/2. \tag{18}$$

The plane normal will have the desired direction if

$$\underset{\sim}{h}_\theta = \underset{\sim}{\Omega}\ \underset{\sim}{X}\ \underset{\sim}{\Phi}\ \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{h} \tag{19}$$

has the form

$$\underset{\sim}{h}_{\theta} = \begin{pmatrix} q \\ 0 \\ 0 \end{pmatrix} . \qquad (20)$$

Equations (17) to (20) can be regarded as the fundamental equations for this diffractometer.

EVALUATING THE ORIENTATION MATRIX

We will now show how the orientation matrix $\underset{\sim}{U}$ can be obtained from the observation of two reflections from non-parallel planes of known indices provided that the cell parameters are known. For reasons which will become apparent we will call these two reflections the primary and secondary orienting reflections. Let their indices be $\underset{\sim}{h}_1$ and $\underset{\sim}{h}_2$, respectively.

From the observation of the instrument angles ω, χ, and ϕ which center the diffracted beam in the counter we can obtain $\underset{\sim}{u}_{\phi}$, the description in the ϕ-axis system of a unit vector which has the direction of the plane normal:

$$\underset{\sim}{u}_{\phi} = \underset{\sim}{\Phi}\,\underset{\sim}{X}\,\underset{\sim}{\Omega}\,\underset{\sim}{u}_{\theta} = \underset{\sim}{\Phi}\,\underset{\sim}{X}\,\underset{\sim}{\Omega} \begin{pmatrix} 1 \\ 0 \\ 0 \end{pmatrix} \qquad (21)$$

or in expanded form:

$$\underset{\sim}{u}_{\phi} = \begin{pmatrix} \cos\omega \cos\chi \cos\phi - \sin\omega \sin\phi \\ \cos\omega \cos\chi \sin\phi + \sin\omega \cos\phi \\ \cos\omega \sin\chi \end{pmatrix}. \qquad (22)$$

In this way two unit vectors $\underset{\sim}{u}_{1\phi}$ and $\underset{\sim}{u}_{2\phi}$ can be obtained from the observed angles of the primary and secondary orienting reflections, respectively.

Since the indices and cell parameters are known we can calculate the scattering vectors in the crystal cartesian system:

$$\left.\begin{aligned} \underset{\sim}{h}_{1c} &= \underset{\sim}{B}\, \underset{\sim}{h}_1 \\ \underset{\sim}{h}_{2c} &= \underset{\sim}{B}\, \underset{\sim}{h}_2. \end{aligned}\right\} \qquad (23)$$

Ideally the desired matrix $\underset{\sim}{U}$ should perform the transformations

$$\left.\begin{aligned} \underset{\sim}{h}_{1\phi} &= \underset{\sim}{U}\, \underset{\sim}{h}_{1c} \\ \underset{\sim}{h}_{2\phi} &= \underset{\sim}{U}\, \underset{\sim}{h}_{2c} \end{aligned}\right\} \qquad (24)$$

and

so that the calculated $\underset{\sim}{h}_{1\phi}$ and $\underset{\sim}{h}_{2\phi}$ have the directions of the observed $\underset{\sim}{u}_{1\phi}$ and $\underset{\sim}{u}_{2\phi}$, respectively. However, because of experimental errors in the angle measurements or uncertainties in the cell parameters, it is not in general possible to find an orthogonal matrix $\underset{\sim}{U}$ which satisfies both conditions. That is to say, the angle subtended by $\underset{\sim}{h}_{1c}$ and $\underset{\sim}{h}_{2c}$ may in general differ from that subtended by $\underset{\sim}{u}_{1\phi}$ and $\underset{\sim}{u}_{2\phi}$.

In order to avoid this difficulty we will require that $\underset{\sim}{h}_{1\phi}$ be parallel to $\underset{\sim}{u}_{1\phi}$ as before, but $\underset{\sim}{h}_{2\phi}$ will only be constrained to lie in the plane of $\underset{\sim}{u}_{1\phi}$ and $\underset{\sim}{u}_{2\phi}$. Thus the primary reflection determines the direction of a vector in the crystal, and the secondary reflection establishes an angle of rotation about this axis.

Define a right-handed orthogonal unit-vector triple, $\underset{\sim}{t}_{1c}$, $\underset{\sim}{t}_{2c}$, $\underset{\sim}{t}_{3c}$, in the crystal cartesian system so that $\underset{\sim}{t}_{1c}$ is parallel to $\underset{\sim}{h}_{1c}$, $\underset{\sim}{t}_{2c}$ lies in the plane of $\underset{\sim}{h}_{1c}$ and $\underset{\sim}{h}_{2c}$, and $\underset{\sim}{t}_{3c}$ is perpendicular to this plane. Define another such triple, $\underset{\sim}{t}_{1\phi}$, $\underset{\sim}{t}_{2\phi}$, $\underset{\sim}{t}_{3\phi}$, in the ϕ-axis system based in the same way on $\underset{\sim}{u}_{1\phi}$ and $\underset{\sim}{u}_{2\phi}$. Then, since these two unit vector triples can be exactly superimposed on each other, the desired orthogonal matrix $\underset{\sim}{U}$ will satisfy exactly the equations

$$\underset{\sim}{t}_{n\phi} = \underset{\sim}{U}\,\underset{\sim}{t}_{nc};\ n = 1,2,3. \tag{25}$$

These three vector equations can be written as one matrix equation

$$\underset{\sim}{T}_{\phi} = \underset{\sim}{U}\,\underset{\sim}{T}_{c} \tag{26}$$

where $\underset{\sim}{T}_{c}$ is the matrix with columns $\underset{\sim}{t}_{1c}$, $\underset{\sim}{t}_{2c}$, and $\underset{\sim}{t}_{3c}$ and $\underset{\sim}{T}_{\phi}$ is similarly constructed from $\underset{\sim}{t}_{1\phi}$, $\underset{\sim}{t}_{2\phi}$, and $\underset{\sim}{t}_{3\phi}$. Then

$$\underset{\sim}{U} = \underset{\sim}{T}_{\phi}\underset{\sim}{T}_{c}^{-1} = \underset{\sim}{T}_{\phi}\underset{\sim}{\tilde{T}}_{c} \tag{27}$$

since $\underset{\sim}{T}_{c}$ can be shown to be orthogonal.

The procedure for obtaining $\underset{\sim}{U}$ in this way is a part

of the algorithm generate UB given in the Appendix. The algorithms triple and normal describe other details of the calculation.

A PROCEDURE FOR USE WHEN THE LATTICE PARAMETERS ARE UNKNOWN

When the unit cell parameters are unknown it is still possible to obtain the matrix $\underset{\sim}{UB}$ if the setting angles can be observed for three reflections with known (or assumed) indices. Given $2\theta_i$, ω_i, χ_i, and ϕ_i for reflection i, we can compute the scattering vector in the phi-axis system:

$$\underset{\sim}{h}_{i\phi} = (2\sin\theta_i/\lambda)\ \underset{\sim}{u}_{i\phi} \tag{28}$$

where $\underset{\sim}{u}_{i\phi}$ is obtained using equation (22). For each of the three reflections the matrix $\underset{\sim}{UB}$ must perform the transformation

$$\underset{\sim}{h}_{i\phi} = \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{h}_i \tag{29}$$

where $\underset{\sim}{h}_i$ is the vector of indices. Then if $\underset{\sim}{H}_\phi$ is a matrix made up of the three column vectors $\underset{\sim}{h}_{i\phi}$, and if $\underset{\sim}{H}$ is similarly constructed from $\underset{\sim}{h}_i$, we have

$$\underset{\sim}{H}_\phi = \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{H} \tag{30}$$

and

$$\underset{\sim}{U}\ \underset{\sim}{B} = \underset{\sim}{H}_\phi\ \underset{\sim}{H}^{-1}. \tag{31}$$

The reflections chosen must correspond to reciprocal

lattice vectors which are not coplanar or the matrix $\underset{\sim}{H}$ will be singular. The indices should be assigned so that the vectors can be described with reference to a right-handed coordinate system, and it can be shown that the determinant $|\underset{\sim}{U}\ \underset{\sim}{B}|$ (which has an absolute value equal to the unit cell volume) will be positive if and only if this condition is met.

Having obtained the matrix $\underset{\sim}{U}\ \underset{\sim}{B}$ it is possible to derive from it the corresponding cell parameters. Let us compute the matrix

$$\widetilde{\underset{\sim}{U}\ \underset{\sim}{B}}\ \underset{\sim}{U}\ \underset{\sim}{B} = \underset{\sim}{\tilde{B}}\ \underset{\sim}{\tilde{U}}\ \underset{\sim}{U}\ \underset{\sim}{B} = \underset{\sim}{\tilde{B}}\ \underset{\sim}{B}. \tag{32}$$

It can be shown that

$$\underset{\sim}{\tilde{B}}\ \underset{\sim}{B} = \underset{\sim}{G}^{-1} \tag{33}$$

where $\underset{\sim}{G}^{-1}$ is the reciprocal metric tensor with elements

$$(G^{-1})_{ij} = \underset{\simeq}{b}_i \cdot \underset{\simeq}{b}_j. \tag{34}$$

Then $\underset{\sim}{G}$ is the metric tensor (see, for example, Patterson, 1959b) with elements

$$G_{ij} = \underset{\simeq}{a}_i \cdot \underset{\simeq}{a}_j \tag{35}$$

and the direct lattice parameters are given by:

$$\left.\begin{aligned} a_i &= G_{ii}^{1/2} \\ \text{and} \qquad & \\ \cos\alpha_i &= G_{jk}/a_j a_k; \quad i \neq j \neq k \neq i. \end{aligned}\right\} \tag{36}$$

The algorithms for these calculations are given in the Appendix as procedures generate UB from three reflections and compute cell parameters from UB.

ANGLE CALCULATIONS FOR SPECIAL CASES

Once the matrix $\underset{\sim}{UB}$ has been evaluated it is possible to obtain

$$\underset{\sim}{h}_\phi = \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{h} \qquad (37)$$

for any set of indices $\underset{\sim}{h}$, and ways of computing instrument angles which bring this vector into the ideal reflecting position will now be discussed. With a four-circle instrument this reflecting condition can be established in an unlimited number of ways corresponding to various values of ψ, the angle of rotation of the sample about the scattering vector. It will be useful to consider two special cases in which one of the instrument angles is fixed at a convenient value.

First let us consider the bisecting position in which ω is constrained to be zero so that the plane of the χ ring bisects the angle defined by the reverse primary and diffracted beams. This arrangement permits access to all reflections with θ below an upper limit, and it is the only position available with most three-circle instruments.

Assume that the diffractometer initially has all angles set to zero. The vector $\underset{\sim}{h}_\phi$ can be brought to the scattering

position by first rotating ϕ to bring it into the plane of the χ ring and then changing χ to bring it to the horizontal plane. The required angle changes are

$$\left.\begin{aligned} \phi &= \text{atan}\ (h_{\phi 2}, h_{\phi 1}) \\ \text{and} \\ \chi &= \text{atan}\ \left[h_{\phi 3}, (h_{\phi 1}{}^2 + h_{\phi 2}{}^2)^{1/2}\right]. \end{aligned}\right\} \quad (38)$$

In the above equations and throughout this paper the expression

$$\alpha = \text{atan}\ (y,x) \quad (39)$$

defines an angle α = arc tan (y/x) in the quadrant for which the signs of $\sin\alpha$ and $\cos\alpha$ are those of y and x, respectively. An algorithm for evaluating the arc tangent in this way is given in the Appendix as procedure atan.

The expressions given above yield angles with $-90^{\circ} \leqslant \chi \leqslant 90^{\circ}$ because the square root is taken as positive. An alternative setting

$$\left.\begin{aligned} \phi' &= 180^{\circ} + \phi \\ \chi' &= 180^{\circ} - \chi \end{aligned}\right\} \quad (40)$$

corresponds to a rotation of 180° about the scattering vector ($\psi' = 180^{\circ} + \psi$).

In the bisecting position the Bragg angle which can be reached may be limited by the fact that the χ ring lies between the counter and the source. In the parallel position

ω is allowed to take values which turn the χ ring past the counter so that its plane is more or less parallel to the reflecting plane. Usually the greatest range can be obtained by constraining χ to be 90^{o}.

Consider the instrument with $\chi = 90^{o}$ and the other angles set to zero. The vector $\underset{\sim}{h}_{\phi}$ can be brought into the horizontal plane by rotating ϕ and it can then be brought to the scattering position by changing ω. The expressions for these angles are

$$\left.\begin{aligned} \phi &= \text{atan}\,(h_{\phi 1}, -h_{\phi 2}) \\ \text{and} \\ \omega &= \text{atan}\left[-(h_{\phi 1}{}^{2} + h_{\phi 2}{}^{2})^{1/2}, h_{\phi 3}\right]. \end{aligned}\right\} \quad (41)$$

Compared to the bisecting position these settings correspond to a 90^{o} rotation about the scattering vector.

Reflections with vectors nearly parallel to the ϕ axis are inaccessible in this arrangement because of interference between the χ ring and the counter or primary beam. The apex angles of the cones which are lost become large at low Bragg angles. Three alternative settings are available:

	1	2	3
ϕ'	$180^{o} + \phi$	ϕ	$180^{o} + \phi$
χ'	90^{o}	-90^{o}	-90^{o}
ω'	$-\omega$	$180^{o} - \omega$	$180^{o} + \omega$
ψ'	$180^{o} + \psi$	$180^{o} + \psi$	ψ

but the use of these may not reduce the amount of interference significantly.

Algorithms for making these calculations are given in the Appendix as procedures angles for bisecting position and angles for parallel position.

ANGLES FOR A SPECIFIED AZIMUTH

We will now consider the problem of computing the diffractometer settings for some specified value of the azimuthal angle, ψ. Let us define an instrument-angle matrix

$$\underset{\sim}{R} = \underset{\sim\sim}{\Omega}\ \underset{\sim}{X}\ \underset{\sim}{\Phi} \tag{42}$$

which transforms a vector from the ϕ-axis system to the θ-axis system. For the vector to be in the scattering position we must have

$$\underset{\sim}{R}\ \underset{\sim}{h}_{\phi} = \underset{\sim}{h}_{\theta} = \begin{pmatrix} q \\ 0 \\ 0 \end{pmatrix} . \tag{43}$$

Choose some diffractometer setting which satisfies this condition and define $\psi = 0$ for this configuration. We can then evaluate

$$\underset{\sim}{R}_{o} = \underset{\sim\sim}{\Omega}_{o}\ \underset{\sim}{X}_{o}\ \underset{\sim}{\Phi}_{o} . \tag{44}$$

In order to rotate the sample about the reflecting-plane normal through an angle ψ measured from this zero position

we generate a new matrix

$$\underset{\sim}{R} = \underset{\sim}{\Psi}\,\underset{\sim}{R}_o \tag{45}$$

where

$$\underset{\sim}{\Psi} = \begin{pmatrix} 1 & 0 & 0 \\ 0 & \cos\psi & \sin\psi \\ 0 & -\sin\psi & \cos\psi \end{pmatrix} . \tag{46}$$

The problem then is to extract from this orthogonal matrix $\underset{\sim}{R}$ the values of the instrument angles ω, χ, and ϕ to which it corresponds.

Expanding equation (42) we have:

$$\underset{\sim}{R} = \begin{pmatrix} \cos\omega\cos\chi\cos\phi-\sin\omega\sin\phi & \cos\omega\cos\chi\sin\phi+\sin\omega\cos\phi & \cos\omega\sin\chi \\ -\sin\omega\cos\chi\cos\phi-\cos\omega\sin\phi & -\sin\omega\cos\chi\sin\phi+\cos\omega\cos\phi & -\sin\omega\sin\chi \\ -\sin\chi\cos\phi & -\sin\chi\sin\phi & \cos\chi \end{pmatrix} \tag{47}$$

and we see that

$$\left.\begin{aligned} \chi &= \operatorname{atan}\left[(R_{31}{}^2 + R_{32}{}^2)^{1/2}, R_{33}\right], \\ \phi &= \operatorname{atan}\,(-R_{32}, -R_{31}), \\ \text{and} \qquad \omega &= \operatorname{atan}\,(R_{13}, -R_{23}). \end{aligned}\right\} \tag{48}$$

(The more obvious expression, $\chi = \arccos R_{33}$, is not used because round-off could cause excessive errors in χ when $R_{33} \approx \pm 1$.) By taking the positive square root in the expression for χ we are choosing $\sin\chi \geqslant 0$ so that $0 \leqslant \chi \leqslant 180^\circ$. An equally valid solution for the same value

of ψ is

$$\left.\begin{aligned} \chi' &= -\chi \\ \phi' &= 180^{\circ} + \phi \\ \omega' &= 180^{\circ} + \omega. \end{aligned}\right\} \quad (49)$$

In practice it is usually the range of ω which is limited by the mechanics of the instrument. The procedure should be to compute angles using equations (48), test ω, and make the transformations (49) if it is out of range. If both solutions are out of range then the specified value of ψ is not accessible for this reflection.

A singular case occurs if $R_{33} = \pm 1$. Then $\cos\chi = \pm 1$, $\sin\chi = 0$, and the matrix becomes

$$\underset{\sim}{R} = \begin{pmatrix} \pm\cos(\omega \pm \phi) & \sin(\omega \pm \phi) & 0 \\ \mp\sin(\omega \pm \phi) & \cos(\omega \pm \phi) & 0 \\ 0 & 0 & \pm 1 \end{pmatrix}. \quad (50)$$

Thus the ω and ϕ motions have become redundant, and this can easily be understood in terms of the instrument geometry when χ is zero or 180°. It can be shown that the continuity of an azimuthal scan can best be attained by selecting $\omega = 90^{\circ}$ for this singular case. The matrix then becomes

$$\underset{\sim}{R} = \begin{pmatrix} -\sin\phi & \cos\phi & 0 \\ \mp\cos\phi & \mp\sin\phi & 0 \\ 0 & 0 & \pm 1 \end{pmatrix} \quad (51)$$

and we have

$$\left.\begin{aligned} \phi &= \text{atan}\,(-R_{11}, R_{12}) \\ \text{and} \qquad & \\ \omega &= 90^{o}. \end{aligned}\right\} \qquad (52)$$

The transformations (49) are still valid for this singular case.

Now let us consider in more detail the choice of the instrument setting at which we define Ψ to be zero. We could, for example, use the bisecting position as a reference, and then we would have

$$\underset{\sim}{R}_{o} = \underset{\sim}{X}_{o}\,\underset{\sim}{\Phi}_{o} \qquad (53)$$

since $\omega_{o} = 0$. But this choice has the disadvantage of depending on the sample mounting so that the definition of Ψ would not in general be comparable for different specimens. To overcome this limitation we will describe a way of defining the reference position in terms of the crystal lattice itself.

Let $\underset{\sim}{h}$ be the plane normal of the reflection to be observed and let us specify a reference vector $\underset{\sim}{h}_{o}$ which is not parallel to $\underset{\sim}{h}$. Then choose as the zero of Ψ that setting for which $\underset{\sim}{h}$ lies in the scattering direction and $\underset{\sim}{h}_{o}$ lies in the horizontal plane of the instrument on the same side as the diffracted beam (i.e., so that in the θ-axis system its z component is zero and its y component is positive).

The computation of $\underset{\sim}{R}_{o}$ based on this definition is analogous to the determination of $\underset{\sim}{U}$ described above. The vectors

$$\left.\begin{aligned} \underset{\sim}{h}_{\phi} &= \underset{\sim}{U}\,\underset{\sim}{B}\,\underset{\sim}{h} \\ \text{and} \qquad & \\ \underset{\sim}{h}_{o\phi} &= \underset{\sim}{U}\,\underset{\sim}{B}\,\underset{\sim}{h}_{o} \end{aligned}\right\} \qquad (54)$$

are first evaluated. Then the matrix $\underset{\sim}{T}_{\phi}$ is constructed with columns equal to $\underset{\sim}{t}_{1\phi}$, $\underset{\sim}{t}_{2\phi}$, and $\underset{\sim}{t}_{3\phi}$, the components of a right-handed orthogonal unit vector triple defined to have $\underset{\sim}{t}_{1\phi}$ parallel to $\underset{\sim}{h}_{\phi}$, $\underset{\sim}{t}_{2\phi}$ in the plane of $\underset{\sim}{h}_{\phi}$ and $\underset{\sim}{h}_{o\phi}$, and $\underset{\sim}{t}_{3\phi}$ perpendicular to this plane.

Now we note that our definition of zero ψ requires the orthogonal matrix $\underset{\sim}{R}_{o}$ to rotate this unit vector triple into coincidence with the axes of the θ coordinate system. The matrix which describes these axes in the θ-system is just the identity matrix so that we have

$$\underset{\sim}{R}_{o}\underset{\sim}{T}_{\phi} = \underset{\sim}{1}$$

and

$$\underset{\sim}{R}_{o} = \underset{\sim}{T}_{\phi}^{-1} = \underset{\sim}{\tilde{T}}_{\phi}. \qquad (55)$$

The algorithm for these calculations is given in the Appendix as the procedure angles for specified psi.

VECTORS FOR CALCULATING ABSORPTION CORRECTIONS

In order to calculate absorption corrections it is generally necessary to compute for each reflection the direction cosines of the diffracted beam and of the reverse primary beam referred to some coordinate system in which the sample shape is described (see, for example, Busing & Levy,

1957). The ϕ-axis system may often be a suitable reference system, and the required direction cosines are just the components of the appropriate unit vectors in this system. Let $\underset{\sim}{p}$ and $\underset{\sim}{d}$ represent unit vectors in the primary and diffracted beam directions, respectively, so that

$$\underset{\sim}{p}_{\ell} = \underset{\sim}{d}_{2\theta} = \begin{pmatrix} 0 \\ 1 \\ 0 \end{pmatrix} . \tag{56}$$

Then the required vectors are

$$\left.\begin{aligned} -\underset{\sim}{p}_{\phi} &= - \underset{\approx}{\tilde{\Phi}}\, \underset{\approx}{\tilde{X}}\, \underset{\approx}{\tilde{N}}\, \underset{\sim}{p}_{\ell} \\ \text{and} \qquad \underset{\sim}{d}_{\phi} &= \underset{\approx}{\tilde{\Phi}}\, \underset{\approx}{\tilde{X}}\, \underset{\approx}{\tilde{M}}\, \underset{\sim}{d}_{2\theta}, \end{aligned}\right\} \tag{57}$$

and expanding we obtain

$$\begin{pmatrix} \sin(\theta \pm \omega)\, \cos\chi \cos\phi \pm \cos(\theta \pm \omega)\, \sin\phi \\ \sin(\theta \pm \omega)\, \cos\chi \sin\phi \mp \cos(\theta \pm \omega)\, \cos\phi \\ \sin(\theta \pm \omega)\, \sin\chi \end{pmatrix} \tag{58}$$

where the upper and lower signs apply to $-\underset{\sim}{p}_{\phi}$ and $\underset{\sim}{d}_{\phi}$, respectively.

If a sample has natural faces it may be preferable to refer its description to the crystal cartesian system. In this case the desired vectors, $-\underset{\sim}{p}_{c}$ and $\underset{\sim}{d}_{c}$, are readily obtained by multiplying $-\underset{\sim}{p}_{\phi}$ and $\underset{\sim}{d}_{\phi}$ by $\underset{\approx}{\tilde{U}}$.

Algorithms for obtaining these vectors are included in the Appendix.

REFINEMENT OF LATTICE AND ORIENTATION PARAMETERS

So far we have established the matrix $\underset{\sim}{UB}$ either from known cell parameters and observations of two reflections or from observations of three reflections alone. A better procedure would be to observe angles for several reflections and to use the method of least squares to refine the cell parameters and orientation parameters simultaneously. Computer programs are available (see, for example, Busing & Levy, 1962) which, when given a list of trial parameters, a set of observations, and a procedure for calculating the quantity comparable with these observations, will refine specified parameters by the method of least squares. Analytical expressions for the required derivatives are not needed since these are computed numerically.

The parameter list includes the three axial lengths and three interaxial angles of the direct unit cell. In some cases these will be subject to constraints imposed by the symmetry of the crystal system. Angles with fixed values of 90° or 120° are simply not varied in the least-squares procedure. Two or more parameters can be constrained to be equal by choosing one of them to be varied and setting the others equal to it. Since numerical derivatives are obtained by recalculating the function after adding an increment to the corresponding parameter, these derivatives will be correct if the constraint is applied immediately after each parameter is incremented.

The wavelength may also be included in the parameter list since it is not always precisely known (especially in neutron diffraction work). It is clear, however, that the wavelength is redundant with the axial lengths and the four of these parameters cannot be adjusted simultaneously.

The sample orientation is represented in the parameter list by the six angles ω_1, χ_1, ϕ_1, ω_2, χ_2, and ϕ_2 for the primary and secondary orienting reflections. Only three of these angles can be varied, however, since only three parameters are required to define orientation. The variables must include two angles of the primary reflection chosen to define the direction of this vector, and one angle of the secondary reflection chosen to measure rotation of the sample about this primary vector. Acceptable sets of variables are listed in Table I for various choices of orienting reflections. For example, if ω_1, χ_1, ω_2, and χ_2 are all near zero and if ϕ_1 and ϕ_2 differ by about 90°, then we see that χ_1, ϕ_1, and χ_2 or ω_1, χ_1, and χ_2 are suitable variables.

After refinement, the angles ω_1, χ_1, and ϕ_1 define the best estimate of the direction of $\underset{\sim}{h}_1$, and the calculated angles for this reflection based on the new parameters will correspond exactly to this vector. The angles ω_2, χ_2, and ϕ_2 no longer define $\underset{\sim}{h}_2$, however, because only one of them has been varied. Instead they represent a vector direction which will yield the best estimate of the orientation matrix $\underset{\sim}{U}$.

Calculation of angles for $\underset{\sim}{h}_2$ will correctly yield the best estimate of a setting for this reflection, but these angles will generally not be the same as the refined parameters.

A reciprocal lattice vector has three independent properties consisting of two directional parameters and a length which is related to the corresponding Bragg angle. We will consider six ways of observing these variables or combinations of them, identifying these ways as observations of types 1 to 6. For each type of observation we will show how the corresponding calculated value can be obtained from the known instrument settings and the assumed trial parameters.

In the course of these calculations it will be convenient to distinguish the instrument dial readings and their matrices by the subscript d (e.g., ϕ_d and $\underset{\sim}{\Phi}_d$) since these will not in general be equal to the ideal angles used earlier in this paper. Similarly, calculated angles and their matrices will be identified by the subscript c.

Type 1 observations. Several ways of measuring the Bragg angle are essentially equivalent to centering the diffracted beam in the counter and using the counter angle, $2\theta_d$, as the observation. The corresponding calculated quantity is $2\theta_c = 2\theta$ where θ is obtained from the trial parameters by means of equations (17) and (18).

Type 2 observations. If the counter angle is adjusted to center the diffracted beam horizontally in the aperture,

then $2\theta_d$ may be used as an observation even though the beam may not be centered vertically.

In deriving the corresponding $2\theta_c$ it will be useful to recall the diffraction equation

$$\underset{\sim}{d} = \underset{\sim}{p} + 2\sin\theta\ \underset{\sim}{u} . \tag{59}$$

Here $\underset{\sim}{d}$, $\underset{\sim}{p}$, and $\underset{\sim}{u}$ are unit vectors in the directions of the diffracted beam, the primary beam, and the scattering vector, respectively. Evaluating $\underset{\sim}{d}$ in the laboratory system we obtain

$$\underset{\sim}{d}_\ell = \begin{pmatrix} (\sin^2 2\theta - 4\sin^2\theta\ u_{\omega 3}{}^2)^{1/2} \\ \cos 2\theta \\ 2\sin\theta\ u_{\omega 3} \end{pmatrix}. \tag{60}$$

Here $d_{\ell 2}$ has been derived from the fact that $\underset{\sim}{d}_\ell$ makes an angle of 2θ with $\underset{\sim}{p}_\ell$ which is directed along the y axis. The component $d_{\ell 3}$ is obtained from the diffraction equation (59) remembering that $p_{\ell 3} = 0$ and that $u_{\ell 3} = u_{\omega 3}$. Finally $d_{\ell 1}$ is derived from the requirement that $\underset{\sim}{d}$ be a unit vector.

The quantity to be computed is the value of the counter angle, $2\theta_c$, which makes $d_{2\theta,1} = 0$. We have

$$\underset{\sim}{d}_{2\theta} = \underset{\sim}{\Theta}_c\ \underset{\sim}{\Theta}_c\ \underset{\sim}{d}_\ell \tag{61}$$

and

$$d_{2\theta,1} = \cos 2\theta_c d_{\ell 1} - \sin 2\theta_c\ d_{\ell 2} = 0 \tag{62}$$

so that

$$2\theta_c = \text{atan}\,(d_{\ell 1}, d_{\ell 2}) \tag{63}$$

and the desired expression is

$$2\theta_c = \text{atan}\,[(\sin^2 2\theta - 4\sin^2\theta\; u_{\omega 3}^2)^{1/2}, \cos 2\theta]. \tag{64}$$

The vector $\underset{\sim}{u}_\omega$ is obtained from the trial parameters and the χ and ϕ dial settings:

$$\underset{\sim}{u}_\omega = \underset{\sim}{X}_d \underset{\sim}{\Phi}_d \underset{\sim}{U}\; \underset{\sim}{B}\; \underset{\sim}{h}/q\ , \tag{65}$$

and the Bragg angle θ is again obtained from equations (17) and (18). It is readily seen that the result reduces to that for type 1 if the scattering vector is horizontal so that $u_{\omega 3} = 0$.

Type 3 observations. It is possible to center the diffracted beam vertically in the counter by adjusting χ_d provided that ω_d is not nearly $\pm$ 90°. Let the value of χ_d for this condition be taken as an observation.

The requirement is that $d_{2\theta,3} = 0$, and from equations (60) and (61) we see that this reduces to $u_{\omega 3} = 0$. Now

$$\underset{\sim}{u}_\omega = \underset{\sim}{X}_c \underset{\sim}{u}_\chi \tag{66}$$

and

$$u_{\omega 3} = -\sin\chi_c\; u_{\chi 1} + \cos\chi_c\; u_{\chi 3} = 0 \tag{67}$$

so that the calculated angle is either

$$\chi_c = \text{atan}\,(u_{\chi 3}, u_{\chi 1}) \tag{68}$$

or

$$\chi_c' = \chi_c + 180^o. \tag{69}$$

Here $\underset{\sim}{u}_\chi$ is obtained from the trial parameters and the ϕ dial setting:

$$\underset{\sim}{u}_\chi = \underset{\sim}{\Phi}_d \underset{\sim}{U} \underset{\sim}{B} \underset{\sim}{h}/q \ . \tag{70}$$

In this case and in others to be described below we have two widely separated solutions both of which are physically reasonable. A simple computational procedure is to select the result which is closest to the observation, adding or subtracting 360^o if necessary to make the quantities comparable. The procedure select described in the Appendix performs this operation.

Type 4 observations. Vertical centering of the diffracted beam can also be obtained by adjusting ϕ_d provided that ω_d is not nearly 0 or 180^o. Let this ϕ_d be taken as an observation.

Again the requirement is that $u_{\omega 3} = 0$, but χ_d is known and ϕ_c is to be calculated. We have

$$\underset{\sim}{u}_\omega = \underset{\sim}{X}_d \underset{\sim}{\Phi}_c \underset{\sim}{u}_\phi \tag{71}$$

and

$$u_{\omega 3} = -\sin\chi_d(\cos\phi_c \ u_{\phi 1} + \sin\phi_c \ u_{\phi 2}) + \cos\chi_d \ u_{\phi 3}. \tag{72}$$

Then the equation for ϕ_c is

$$\sin\chi_d\ u_{\phi 1}\ \cos\phi_c + \sin\chi_d\ u_{\phi 2}\ \sin\phi_c = \cos\chi_d\ u_{\phi 3} \quad (73)$$

where

$$\underset{\sim}{u}_\phi = \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{h}/q\ . \quad (74)$$

Equation (73) is an expression of the form

$$e\ \cos\ \phi_c + f\ \sin\ \phi_c = g$$

which has solutions

$$\left.\begin{aligned} \phi_c &= \eta \pm \gamma \\ &\text{where} \\ \eta &= \text{atan}\ (f,e) \\ \gamma &= \text{atan}[(e^2 + f^2 - g^2)^{1/2}, g]. \end{aligned}\right\} \quad (75)$$

Again the appropriate solution is chosen by using procedure select. The two solutions become complex or equal if $e^2 + f^2 - g^2 \leqslant 0$, but this does not occur if the type of observation is chosen in a sensible way. An algorithm for the solution of an equation of this form is given in the Appendix as procedure trig eq.

Observations of types 5 and 6. Consider the observation that the Bragg condition is satisfied so that the intensity of the reflection is maximized. It is important to note that this condition can be observed with configurations other than that of Fig. 1a if the counter aperture

is large enough. The requirement is only that the scattering vector $\underset{\sim}{u}$ makes an angle of $90^{o} + \theta$ with the primary beam direction, that is

$$u_{\ell 2} = -\sin\theta . \tag{76}$$

Now

$$\underset{\sim}{u}_{\ell} = \underset{\sim}{N}_{c}\ \underset{\sim}{u}_{\omega} \tag{77}$$

and

$$u_{\ell 2} = -\sin \mathcal{V}_{c}\ u_{\omega 1} + \cos \mathcal{V}_{c}\ u_{\omega 2} \tag{78}$$

so that the condition becomes

$$u_{\omega 2} \cos \mathcal{V}_{c} - u_{\omega 1} \sin \mathcal{V}_{c} = -\sin\theta . \tag{79}$$

Here $\underset{\sim}{u}_{\omega}$ can be evaluated from the trial parameters and instrument settings:

$$\underset{\sim}{u}_{\omega} = \underset{\sim}{X}_{d}\ \underset{\sim}{\Phi}_{d}\ \underset{\sim}{U}\ \underset{\sim}{B}\ \underset{\sim}{h}/q\ , \tag{80}$$

and θ is calculated from equations (17) and (18). The procedure trig eq can then be used to obtain two solutions for $\mathcal{V}_{c}$.

Let a type 5 observation be the value of ω_{d} which establishes the Bragg condition when $2\theta_{d}$ is fixed. Then the corresponding calculated value is

$$\omega_{c} = \mathcal{V}_{c} - 2\theta_{d}/2\ . \tag{81}$$

Let a type 6 observation be the value of $2\theta_d$ which establishes the Bragg condition for a given ω_d. Then the calculated quantity is

$$2\theta_c = 2(\mathcal{V}_c - \omega_d). \qquad (82)$$

In each case there will be two computed values corresponding to the two solutions for $\mathcal{V}_c$. The procedure select may be used to choose the appropriate one.

The algorithms for calculating the angles corresponding to the six types of observations are given in the Appendix as the single real procedure y calc.

We have used three different schemes for making observations for least-squares refinement. With a 4-circle diffractometer it is possible to vary ω_d to establish the Bragg condition while centering the reflection vertically in the counter by adjusting χ_d or ϕ_d. The reflection can then be centered horizontally by changing $2\theta_d$ while using a compensating ω_d motion to hold the crystal fixed in the laboratory system. The resulting settings are used as three observations of types 2, 3 or 4, and 5, and both the cell parameters and orientation parameters are adjusted. In practice it makes little difference if the $2\theta_d$ measurement is used as a type 1 observation rather than type 2.

Measurements of the Bragg angle can be used as type 1 observations for the determination of cell parameters. Such observations contain no information about the orientation and

the orientation parameters should not be varied. In x-ray work it is difficult to assign an effective value to λ unless the α-doublet is resolved. For the most accurate work, therefore, the observations should be limited to regions of high Bragg angle.

Observations of type 6 can be extracted from the output data of any 3- or 4-circle instrument which records the intensity profile for a θ-2θ scan. For several years we have routinely obtained such observations from the paper-tape output of our 3-circle neutron diffractometer and used them to improve the cell and orientation parameters for subsequent angle calculations.

In principle it is possible to include in the list of variables parameters which measure the systematic errors of the experiment. These would include angular errors such as scale zero corrections or inaccurately directed instrument shafts as well as displacement errors due to non-intersecting axes or a poorly centered sample. Although we have found the adjustment of certain error parameters to be useful, we will present no further discussion of the method at this time.

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REFERENCES

Arndt, U. W. & Phillips, D. C. (1957). Acta Cryst. 10, 508.

Baumann, R., Feliciano, M., Bauer, F. L. & Samelson, K. (1964). Introduction to ALGOL. Englewood Cliffs, New Jersey: Prentice-Hall.

Busing, W. R., Ellison, R. D. & Levy, H. A. (1965). Abstracts of the American Crystallographic Association Annual Meeting, Gatlinburg, Tennessee, p 59.

Busing, W. R. & Levy, H. A. (1957). Acta Cryst. 10, 180.

Busing, W. R. & Levy, H. A. (1962). OR GLS, A General FORTRAN Least Squares Program. Oak Ridge: ORNL-TM-271.

Busing, W. R., Smith, H. G., Peterson, S. W. & Levy, H. A. (1964). J. Phys., Paris, 25, 495.

Furnas, T. C. & Harker, D. (1955). Rev. Sci. Inst. 26, 449.

Patterson, A. L. (1959a). International Tables for X-ray Crystallography, Vol. II, p 61. Birmingham: Kynoch.

Patterson, A. L. (1959b). Ibid, p 56.

Rollett, J. S. (1965). Computing Methods in Crystallography, pp 22-23, 28-31. Oxford: Pergamon.

Santoro, A. & Zocchi, M. (1964). Acta Cryst. 17, 597.

Willis, B. T. M. (1961). Some Geometrical Properties of the Three-Circle Goniometer. Harwell: AERE-R3773.

Wooster, W. A. (1964). Acta Cryst. 17, 1348.

Table I. Acceptable sets of variables for the refinement of orientation listed as a function of ω_1, χ_1, ω_2, χ_2, and $\phi_2 - \phi_1$. Values of 0 designate angles within about 45° of 0 or 180°, and values of 90 are used for angles within about 45° of $\pm 90^\circ$.

ω_1	χ_1	Two variables	ω_2	χ_2	$\phi_2 - \phi_1$	Third variable
0	0	χ_1 and ϕ_1 or	0	0	0	‖
			0	0	90	χ_2
		ω_1 and χ_1	0	90	0	ω_2
			0	90	90	χ_2
			90	0	0	*
			90	0	90	‖
			90	90	0	ω_2
			90	90	90	‖
0	90	ω_1 and χ_1	0	0	0 or 90	ω_2 or ϕ_2
			0	90	0 or 90	‖
			90	0	0 or 90	ω_2 or ϕ_2
			90	90	0 or 90	ϕ_2
90	0	*				
90	90	ω_1 and ϕ_1	0	0	0	χ_2
			0	0	90	‖
			0	90	0	χ_2
			0	90	90	ω_2
			90	0	0	‖
			90	0	90	*
			90	90	0	‖
			90	90	90	ω_2

‖The two orienting reflections are parallel or nearly so. A different pair should be chosen.

*No instrument variable is available to adjust this vector in the desired way. Another reflection or another setting of this reflection should be used.

APPENDIX

We present here algorithms for several of the procedures which have been described. The language used is Algol 60 (see, for example, Baumann, Feliciano, Bauer & Samelson, 1964) except that, following the precedent of several hardware representations, an asterisk (*) is used to denote multiplication.

Real variables and arrays.

The following identifiers are assumed to be declared for use by the algorithms. Those names with dimensions represent arrays. All others describe real variables. The corresponding mathematical symbols which were used in the text are also listed.

a[1:3]	a_i	Axial lengths of the direct cell in Ångstrom units.
alpha[1:3]	α_i	Interaxial angles of the direct unit cell in degrees.
cosa[1:3]	$\cos\alpha_i$	
sina[1:3]	$\sin\alpha_i$	
b[1:3]	b_i	Axial lengths of the reciprocal cell in reciprocal Ångstrom units.
cosb[1:3]	$\cos\beta_i$	Cosine and sine of the interaxial angles of the reciprocal cell.
sinb[1:3]	$\sin\beta_i$	
B[1:3,1:3]	$\underset{\sim}{B}$	Matrix which transforms a reciprocal lattice vector to the crystal cartesian system.

theta	θ	Instrument angles in degrees as defined in the text.
two theta	2θ	
omega	ω	
chi	χ	
phi	ϕ	
two thetan, omegan, chin, phin (n=1,2,3)		Instrument angles in degrees for reflections used to define orientation.
two theta calc[1:2]	$2\theta_c$	Calculated values of instrument angles in degrees for use in least-squares refinement when it is necessary to distinguish these from the ideal angles. Each array contains two possible solutions for the angle.
omega calc[1:2]	ω_c	
chi calc[1:2]	χ_c	
phi calc[1:2]	ϕ_c	
two theta dial	$2\theta_d$	Instrument angle settings in degrees at which an observation for use in least-squares refinement is made.
omega dial	ω_d	
chi dial	χ_d	
phi dial	ϕ_d	
c		Quantity used in calculating reciprocal cell parameters.
calc[1:2]		Two possible solutions for an angle in degrees.
Chi dial[1:3,1:3]	$\underset{\sim}{X}_d$	Matrix which transforms a vector from the chi-axis system to the omega-axis system.
circle		Integral multiple of 360 degrees.
d phi[1:3]	$\underset{\sim}{d}_\phi$	Unit vector in the direction of the diffracted beam described in the phi-axis system, the crystal cartesian system, or the laboratory system, respectively.
d cryst[1:3]	$\underset{\sim}{d}_c$	
d lab[1:3]	$\underset{\sim}{d}_\ell$	

delta	$\theta \pm \omega$	
epsilon		A small positive number chosen to be safely larger than expected round-off errors.
eta	η	Quantities used in solving the trigonometric equation.
gamma	γ	
e	e	Known coefficients in the trigonometric equation.
f	f	
g	g	
G[1:3,1:3]	$\underset{\sim}{G}$	Direct and reciprocal metric tensors.
G inv[1:3,1:3]	$\underset{\sim}{G}^{-1}$	
h[1:3]	$\underset{\sim}{h}$	Reciprocal lattice vector with components equal to the indices of a reflection.
h cryst[1:3]	$\underset{\sim}{h}_c$	Vector $\underset{\sim}{h}$ described in the crystal cartesian and phi-axis systems.
h phi[1:3]	$\underset{\sim}{h}_\phi$	
hn[1:3]		Vector $\underset{\sim}{h}$ for reflections used to define orientation.
hn cryst[1:3]	n = 1,2,3	
hn phi[1:3]		
H[1:3,1:3]	$\underset{\sim}{H}$	Matrix with vectors hn as its columns.
H inv[1:3,1:3]	$\underset{\sim}{H}^{-1}$	
H phi[1:3,1:3]	$\underset{\sim}{H}_\phi$	Matrix with vectors hn phi as its columns.
hz[1:3]	$\underset{\sim}{h}_o$	Indices of a reference reflection used to define zero of psi.
hz phi[1:3]	$\underset{\sim}{h}_{o\phi}$	Vector of the reference reflection in phi-axis system.

i j k		Integers used as indices in for statements.
lambda	λ	Wavelength in Angstrom units.
min diff		Minimum difference between observed and calculated angles.
minus p phi[1:3]	$-\underset{\sim}{p}_{\phi}$	Unit vector in direction of the reverse primary beam described in phi-axis system or crystal cartesian system.
minus p cryst[1:3]	$-\underset{\sim}{p}_{c}$	
nu calc[1:2]	ν_c	Two calculated values for $\nu = \theta + \omega$.
Phi dial[1:3,1:3]	$\underset{\sim}{\Phi}_d$	Matrix which transforms a vector from the phi-axis system to the chi-axis system.
psi	ψ	Azimuthal angle in degrees as defined in the text.
Psi[1:3,1:3]	$\underset{\sim}{\Psi}$	Matrix which rotates a vector about the x-axis by an angle psi.
q	q	Length of the vector $\underset{\sim}{h}$ in Angstrom units.
R[1:3,1:3]	$\underset{\sim}{R}$	Instrument angle matrix. $\underset{\sim}{R} = \underset{\sim}{\Omega X \Phi}$.
Rz[1:3,1:3]	$\underset{\sim}{R}_o$	Matrix $\underset{\sim}{R}$ for zero psi.
Rz trans[1:3,1:3]	$\underset{\sim}{\tilde{R}}_o$	Transpose of matrix $\underset{\sim}{R}_o$.
sign		Plus or minus one.
sin chi	$\sin\chi$	
sin theta	$\sin\theta$	
T[1:3,1:3]	$\underset{\sim}{T}$	Matrix with columns equal to unit vectors forming a right-handed orthogonal triple.

T cryst[1:3,1:3]	$\underset{\sim}{T}_c$	Matrix T referred to the crystal cartesian system and the phi-axis system, respectively.
T phi[1:3,1:3]	$\underset{\sim}{T}_\phi$	
T cryst trans[1:3,1:3]	$\widetilde{\underset{\sim}{T}}_c$	
tn[1:3], n = 1,2,3		Unit vectors forming a right-handed orthogonal triple.
type		Integer which defines the type of measurement made for least-squares refinement. See text.
U[1:3,1:3]	$\underset{\sim}{U}$	Orientation matrix which transforms a vector from the crystal cartesian system to the phi-axis system.
U trans[1:3,1:3]	$\widetilde{\underset{\sim}{U}}$	Transpose of matrix $\underset{\sim}{U}$.
u[1:3]		General unit vector.
u phi[1:3]	$\underset{\sim}{u}_\phi$	Unit vector in the scattering direction described in the phi-, chi-, or omega-axis systems.
u chi[1:3]	$\underset{\sim}{u}_\chi$	
u omega[1:3]	$\underset{\sim}{u}_\omega$	
un phi[1:3], n = 1,2		Unit vectors corresponding to reflections used to define the orientation.
UB[1:3,1:3]	$\underset{\approx}{UB}$	
UB trans[1:3,1:3]	$\widetilde{\underset{\approx}{UB}}$	
v[1:3]		General vectors.
w[1:3]		
vn[1:3], n = 1,2		Two vectors used to define a unit vector triple.
x		Arguments for atan(y,x).
y		
y calc		Calculated quantity corresponding to an observation for least-squares refinement.
y obs		Observed quantity for least-squares refinement.

Procedures.

The following procedures are defined for use by the algorithms. All matrices and vectors have dimensions M[1:3,1:3] and v[1:3], respectively.

acos(x)	Given x, compute α in degrees so that x = cosα. $0 \leqslant \alpha \leqslant 180^{o}$.
arctan(x)	Given x, compute α in degrees so that x = tanα. $-90^{o} < \alpha < 90^{o}$.
asin(x)	Given x, compute α in degrees so that x = sinα. $-90^{o} \leqslant \alpha \leqslant 90^{o}$.
columns(v1,v2,v3,M)	Given vectors v1, v2, and v3, store them as columns 1,2, and 3, respectively, of the matrix M.
constrain	Set those cell parameters chosen as dependent variables in terms of those chosen as independent in order to maintain the crystal symmetry in a least-squares refinement.
cos(α)	Given an angle α in degrees, compute its cosine.
invert(M,M inv)	Given a matrix M, compute its inverse, M inv.
MM(X,Y,Z)	Given matrices X and Y, compute the product matrix Z = XY.
Mv(X,y,z)	Given matrix X and vector y, compute the product vector z = Xy.
out of range	A Boolean procedure the value of which is true if the computed angle settings are not accessible to the diffractometer.
set j and k	Given i = 1, 2, or 3, set j = mod(i,3) + 1 and k = mod(j,3) + 1 where mod(n,m) is the remainder of n/m.
sin(α)	Given α in degrees, compute its sine.

transpose(M,M trans)	Given matrix M, store its transpose, M trans.
unit(v,u)	Given a non-null vector v, compute vector u, a unit vector parallel to v.
x rot(α,M) y rot(α,M) z rot(α,M)	Given an angle α in degrees, store the matrix M which rotates about the x-, y-, or z-axis, respectively, in the sense defined by equations (46), (9), and (8).

Algorithms.

For simplicity we have omitted tests for conditions which lead to attempted division by zero or which result in a negative radicand. It is left to the user to determine the best way to treat such situations.

```
procedure generate B;
comment  Given the direct cell parameters a and alpha,
   compute the matrix B which transforms a vector from
   the reciprocal lattice system to the crystal
   cartesian system;
begin
   for i:=1,2,3 do
      begin
         cosa[i]:=cos(alpha[i]);
         sina[i]:=sin(alpha[i])
      end;
   c:=sqrt(1-cosa[1]↑2-cosa[2]↑2-cosa[3]↑2
         +2*cosa[1]*cosa[2]*cosa[3]);
   for i:=1,2,3 do
      begin
         set j and k;
         b[i]:=sina[i]/(a[i]*c);
         cosb[i]:=(cosa[j]*cosa[k]-cosa[i])
               /(sina[j]*sina[k]);
         sinb[i]:=sqrt(1-cosb[i]↑2)
      end;
   B[1,1]:=b[1];
   B[2,1]:=0;
   B[3,1]:=0;
   B[1,2]:=b[2]*cosb[3];
   B[2,2]:=b[2]*sinb[3];
```

```
    B[3,2]:=0;
    B[1,3]:=b[3]*cosb[2];
    B[2,3]:=-b[3]*sinb[2]*cosa[1];
    B[3,3]:=1/a[3]
end;

procedure generate UB;
comment  Given the matrix B and the indices and angle
    settings h1, phi1, chi1, omega1, h2, phi2, chi2,
    and omega2 for the primary and secondary orienting
    reflections, respectively, compute the matrix UB
    which transforms a vector from the reciprocal lattice
    system to the phi-axis system;
begin
    Mv(B,h1,h1 cryst);
    Mv(B,h2,h2 cryst);
    compute u phi(omega1,chi1,phi1,u1 phi);
    compute u phi(omega2,chi2,phi2,u2 phi);
    triple(h1 cryst,h2 cryst,T cryst);
    triple(u1 phi,u2 phi,T phi);
    transpose(T cryst,T cryst trans);
    MM(T phi,T cryst trans,U);
    MM(U,B,UB)
end;
```

```
procedure generate UB from three reflections;
comment  Given the instrument angles and indices for
   three reflections, compute the matrix UB which
   transforms a vector from the reciprocal lattice
   system to the phi-axis system;
begin
   compute h phi(two theta1,omega1,chi1,phi1,h1 phi);
   compute h phi(two theta2,omega2,chi2,phi2,h2 phi);
   compute h phi(two theta3,omega3,chi3,phi3,h3 phi);
   columns(h1 phi,h2 phi,h3 phi,H phi);
   columns(h1,h2,h3,H);
   invert(H,H inv);
   MM(H phi,H inv,UB)
end;

procedure compute cell parameters from UB;
comment  Given the matrix UB which transforms a vector
   from the reciprocal lattice system to the phi-axis
   system, compute the cell parameters a and alpha;
begin
   transpose(UB,UB trans);
   MM(UB trans,UB,G inv);
   invert(G inv,G);
   for i:=1,2,3 do
      a[i]:=sqrt(G[i,i]);
```

```
    for i:=1,2,3 do
       begin
          set j and k;
          alpha[i]:=acos(G[j,k]/(a[j]*a[k]))
       end
end;

procedure compute u phi(omega,chi,phi,u phi);
real omega,chi,phi;
array u phi;
comment  Given instrument angles omega, chi,
   and phi, compute u phi, the unit scattering
   vector in the phi-axis system;
begin
   u phi[1]:=cos(omega)*cos(chi)*cos(phi)
         -sin(omega)*sin(phi);
   u phi[2]:=cos(omega)*cos(chi)*sin(phi)
         -sin(omega)*cos(phi);
   u phi[3]:=cos(omega)*sin(chi)
end;
```

```
procedure compute h phi(two theta,omega,chi,phi,h phi);
real two theta,omega,chi,phi;
array h phi;
comment   Given instrument angles two theta, omega, chi,
   and phi, compute h phi, the scattering vector in the
   phi-axis system;
begin
   compute u phi(omega,chi,phi,u phi);
   q:=2*sin(two theta/2)/lambda;
   for i:=1,2,3 do
      h phi[i]:=q*u phi[i]
end;

procedure angles for bisecting position;
comment   Given the matrix UB and the indices h of a
   reflection, compute the setting angles phi, chi,
   and two theta for an omega of zero;
begin
   Mv(UB,h,h phi);
   phi:=atan(h phi[2],h phi[1]);
   chi:=atan(h phi[3],sqrt(h phi[1]↑2+h phi[2]↑2));
   omega:=0;
   compute two theta
end;
```

```
procedure angles for parallel position;
comment  Given the matrix UB and the indices h of a
   reflection, compute the setting angles phi, omega,
   and two theta, for a chi of 90 degrees;
begin
   Mv(UB,h,h phi);
   phi:=atan(h phi[1],-h phi[2]);
   chi:=90;
   omega:=atan(-sqrt(h phi[1]↑2+h phi[2]↑2),h phi[3]);
   compute two theta
end;

procedure angles for specified psi;
comment  Given the matrix UB, the indices h of a
   reflection, the desired azimuthal angle psi, and
   the indices hz of a reference reflection used to
   define psi=0, compute the setting angles phi, chi,
   omega, and two theta;
begin
   Mv(UB,h,h phi);
   compute two theta;
   Mv(UB,hz,hz phi);
   triple(h phi,hz phi,Rz trans);
   transpose(Rz trans,Rz);
   x rot(psi,Psi);
   MM(Psi,Rz,R);
```

```
    sin chi:=sqrt(R[3,1]↑2+R[3,2]↑2);
    chi:=atan(sin chi,R[3,3]);
    if sin chi>epsilon then
       begin
          phi:=atan(-R[3,2],-R[3,1]);
          omega:=atan(-R[2,3],R[1,3])
       end
    else
       begin
          phi:=atan(-R[1,1],R[1,2]);
          omega:=90
       end;
    if out of range then
       begin
          phi:=180+phi;
          chi:=-chi;
          omega:=180+omega
       end
end;
```

```
procedure compute two theta;
comment  Given h phi, the scattering vector in a
   cartesian system, compute the ideal counter setting
   two theta;
begin
   two theta:=2*asin(lambda*sqrt(h phi[1]↑2+h phi[2]↑2
         +h phi[3]↑2)/2)
end;

procedure absorption vectors in phi system;
comment  Given the instrument angles two theta, omega,
   chi, and phi, generate two unit vectors in the phi-axis
   system, minus p phi and d phi, parallel to the reverse
   primary beam and to the diffracted beam, respectively;
begin
   absorption vector(1,minus p phi);
   absorption vector(-1,d phi)
end;

procedure absorption vectors in crystal system;
comment  Given the orientation matrix U and the instru-
   ment angles two theta, omega, chi, and phi, generate
   two unit vectors in the crystal cartesian system,
   minus p cryst and d cryst, parallel to the reverse
   primary beam and to the diffracted beam, respectively;
```

```
begin
   absorption vectors in phi system;
   transpose(U,U trans);
   Mv(U trans,minus p phi,minus p cryst);
   Mv(U trans,d phi,d cryst)
end;

procedure absorption vector(sign,v phi);
real sign;
array v phi;
comment  Given the instrument angles two theta, omega,
   chi, and phi, generate a unit vector in the phi-axis
   system parallel to the reverse primary beam or to the
   diffracted beam according to whether sign is plus one
   or minus one, respectively;
begin
   delta:=two theta/2+sign*omega;
   v phi[1]:=sin(delta)*cos(chi)*cos(phi)
         +sign*cos(delta)*sin(phi);
   v phi[2]:=sin(delta)*cos(chi)*sin(phi)
         -sign*cos(delta)*cos(phi);
   v phi[3]:=sin(delta)*sin(chi)
end;
```

```
real procedure y calc;
comment    Given an observation y obs of a specified
   type on a reflection with indices h, and given the
   cell parameters and wavelength a, alpha, and lambda
   and the orientation information h1, phi1, chi1,
   omega1, h2, phi2, chi2, and omega2, compute y calc
   corresponding to this observation.  For some types
   of measurements the instrument dial settings, two
   theta dial, omega dial, chi dial, and phi dial, at
   which the observation was made are also required;
begin
   constrain;
   generate B;
   Mv(B,h,h cryst);
   sin theta:=lambda*sqrt(h cryst[1]↑2+h cryst[2]↑2
         +h cryst[3]↑2)/2;
   theta:=asin(sin theta);
   if type=1 then
type 1:
      begin
         y obs:=two theta dial;
         two theta calc[1]:=2*theta;
         two theta calc[2]:=-2*theta;
         y calc:=select(two theta calc);
         go to END
      end;
```

```
not type 1:
   generate UB;
   Mv(UB,h,h phi);
   unit(h phi,u phi);
   if type=4 then
type 4:
      begin
         y obs:=phi dial;
         trig eq(sin(chi dial)*u phi[1],sin(chi dial)
               *u phi[2],cos(chi dial)*u phi[3],
               phi calc);
         y calc:=select(phi calc);
         go to END
      end;
not type 1 or 4:
   z rot(phi dial,Phi dial);
   Mv(Phi dial,u phi,u chi);
   if type=3 then
type 3:
      begin
         y obs:=chi dial;
         chi calc[1]:=atan(u chi[3],u chi[1]);
         chi calc[2]:=180+chi calc[1];
         y calc:=select(chi calc);
         go to END
      end;
```

```
not type 1 or 3 or 4:
   y rot(chi dial,Chi dial);
   Mv(Chi dial,u chi,u omega);
   trig eq(u omega[2],-u omega[1],-sin theta,nu calc);
   if type=5 then
type 5:
      begin
         y obs:=omega dial;
         omega calc[1]:=nu calc[1]-two theta dial/2;
         omega calc[2]:=nu calc[2]-two theta dial/2;
         y calc:=select(omega calc);
         go to END
      end;
   if type=6 then
type 6:
      begin
         y obs:=two theta dial;
         two theta calc[1]:=2*(nu calc[1]-omega dial);
         two theta calc[2]:=2*(nu calc[2]-omega dial);
         y calc:=select(two theta calc);
         go to END
      end;
```

```
   if type=2 then
type 2:
      begin
         y obs:=two theta dial;
         d lab[1]:=sqrt((sin(2*theta))↑2
               -(2*u omega[3]*sin theta)↑2);
         d lab[2]:=cos(2*theta);
         two theta calc[1]:=atan(d lab[1],d lab[2]);
         two theta calc[2]:=-two theta calc[1];
         y calc:=select(two theta calc)
      end;
END:end;

real procedure atan(y,x);
real y,x;
comment  Given x and y, the components of a
   two-dimensional vector, compute the angle in degrees
   subtended by the vector and the x axis.
   -180<atan(y,x)≤180;
begin
   if y=0 and x=0 then
      begin
         atan:=0;
         go to END
      end;
```

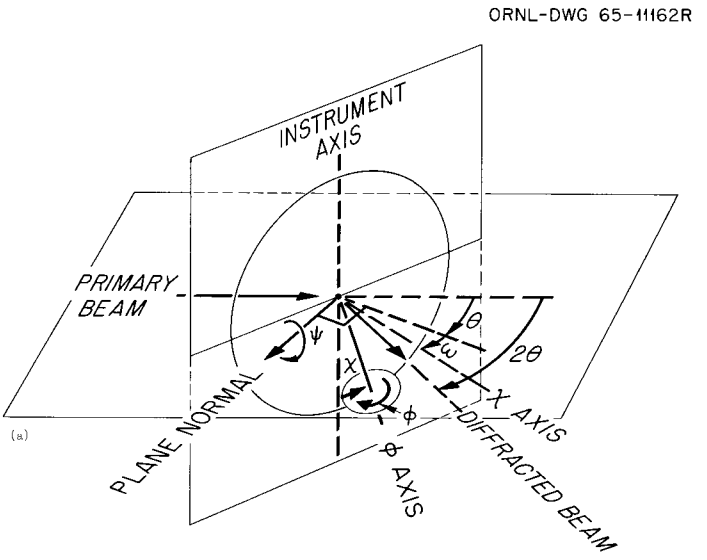
```
    if abs(y)<abs(x) then
       atan:=arctan(abs(y/x))
    else
       atan:=90-arctan(abs(x/y));
    if x<0 then
       atan:=180-atan;
    if y<0 then
       atan:=-atan;
END:end;

procedure trig eq(e,f,g,calc);
real e,f,g;
array calc;
comment  Given the real variables e, f, and g, solve
   the equation e*cos(calc)+f*sin(calc)=g.  The two
   solutions are stored at calc[1] and calc[2];
begin
   eta:=atan(f,e);
   gamma:=atan(sqrt(e↑2+f↑2-g↑2),g);
   calc[1]:=eta+gamma;
   calc[2]:=eta-gamma
end;
```

```
real procedure select(calc);
array calc;
comment   Given two calculated angles calc[1] and
   calc[2], choose the one which is closest to y obs,
   adding or subtracting full circles if necessary;
begin
   min diff:=180;
   for i:=1,2 do
      for circle:=-720 step 360 until 720 do
         if abs(calc[i]+circle-y obs)<min diff then
            begin
               min diff:=abs(calc[i]+circle-y obs);
               select:=calc[i]+circle
            end
end;
```

```
procedure normal(v,w,u);
array v,w,u;
comment  Given two vectors v and w, generate a unit
   vector u perpendicular to them in the direction of
   the vector product [vw];
begin
   u[1]:=v[2]*w[3]-v[3]*w[2];
   u[2]:=v[3]*w[1]-v[1]*w[3];
   u[3]:=v[1]*w[2]-v[2]*w[1];
   unit(u,u)
end;

procedure triple(v1,v2,T);
array v1,v2,T;
comment  Given the vectors v1 and v2, generate the
   matrix T with columns equal to the orthogonal unit
   vectors t1, t2, and t3 which form a right-handed
   system chosen so that t1 is parallel to v1, t2 lies
   in the plane of v1 and v2, and t3 is perpendicular
   to that plane;
begin
   unit(v1,t1);
   normal(v1,v2,t3);
   normal(t3,t1,t2);
   columns(t1,t2,t3,T)
end;
```



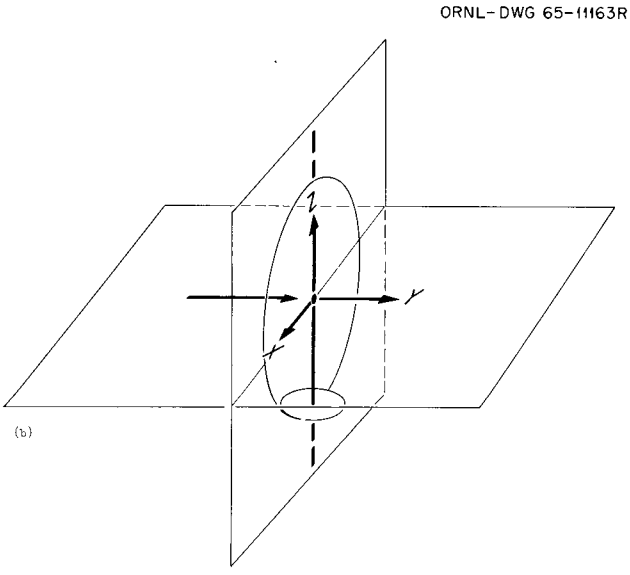


Figure 1. Schematic representation of a 4-circle diffractometer.

a. The configuration when each instrument angle has a value in the first quadrant.

b. The instrument with all angles set to zero. The coordinate axes are those of the ϕ-axis, χ-axis, ω-axis, θ-axis, 2θ-axis, and laboratory systems which are all coincident under these conditions.

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